

Optical Spectrum Analyzer AQ6317B

High-accuracy and high-resolution optical spectrum analyzer
for evaluating D-WDM systems and components.



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The AQ6317B is an advanced optical spectrum analyzer for a wide range of applications, including light source evaluation, measurement of loss wavelength characteristics in optical devices, and waveform analysis of WDM (Wavelength Division Multiplexing) systems.

Especially at C-band and L-band, the unit achieves high wavelength accuracy and wavelength linearity, and can evaluate optical devices for WDM. Analysis functions make operation and expandability simple.

The AQ6317B contains the latest Ando technology for optical spectrum analyzers. A reference equipment for the next generation.

In comparison with the former model, the wavelength accuracy of the AQ6317B has been improved to ± 20 pm, and it is specified as for the L-band as well. WDM analysis function and notch width analysis function are improved, and multi-channel NF analysis function and optical filter analysis function are newly added. It has become much easier to use with other improvements, such as sweep speed-up.

Features

● Wide dynamic range for 50 GHz WDM-Signals

The dynamic range is 70 dB at peak ± 0.4 nm, and 60 dB at peak ± 0.2 nm. High-resolution measurement achieves wide dynamic range with 50 GHz spacing WDM system.

● High wavelength accuracy

Provides ± 0.02 nm wavelength accuracy at 1520 to 1580 nm, and ± 0.04 nm at 1580 to 1620 nm, with ± 0.01 nm wavelength linearity, making it especially useful for high-precision loss wavelength characteristics and other evaluation of WDM devices. The wavelength scale indicates both in air and in vacuum.

● High wavelength resolution

Achieves wavelength resolution of 0.015 nm.

● Versatile analysis functions

Analysis functions for WDM and other optical devices (LD, LED, FBG, etc.).

● Synchronous sweep

In conjunction with an AQ4321 Tunable Laser Source, much higher wavelength resolution/wide dynamic range can be achieved by high-speed synchronous sweep.

● High sensitivity

High sensitivity allows measurement of light at down to -90 dBm, covering from 1200 to 1650 nm.

● Low polarization dependency

Measurements such as gain of optical amplifier can be proceeded accurately because polarization dependency is suppressed as low as ± 0.05 dB.

● High-level accuracy

Accurate within ± 0.3 dB.

● High power measurement: Max. +20 dBm (100 mW)

Even high-power output from an optical amplifier can be measured directly without an optical attenuator.

● 9.4-inch color LCD

● Pulsed light can be measured

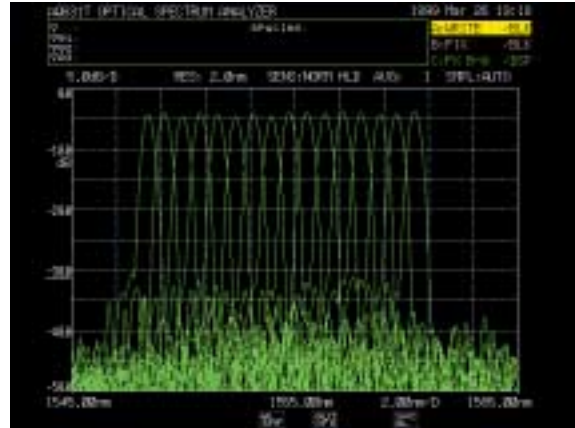
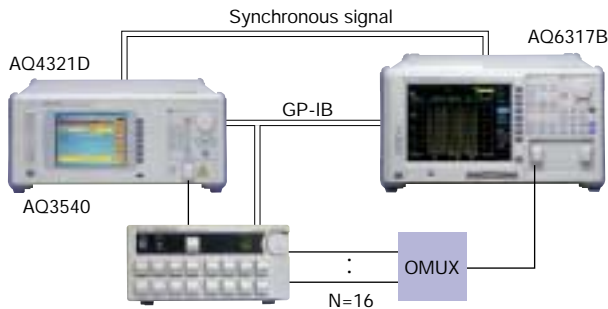
● Three individual trace memories

Applications

● Optical Multiplexer evaluation

In conjunction with the AQ4321 Tunable Laser Source, the AQ6317B can achieve high wavelength resolution/wide dynamic range with high-speed synchronous sweep function, and result insertion loss, passed central wavelength and linearity as evaluation parameter of optical MUX/DEMUX.

Configuration example for measurement with synchronous sweep function

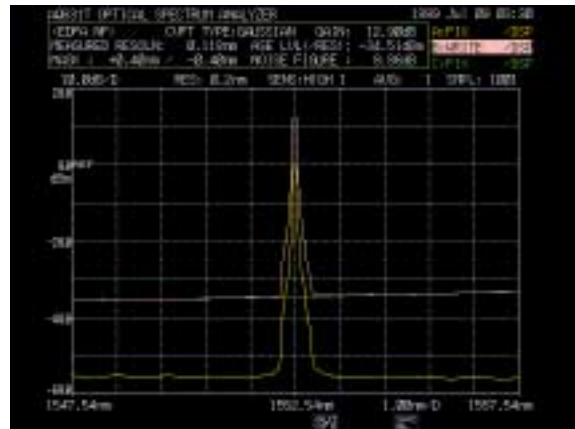
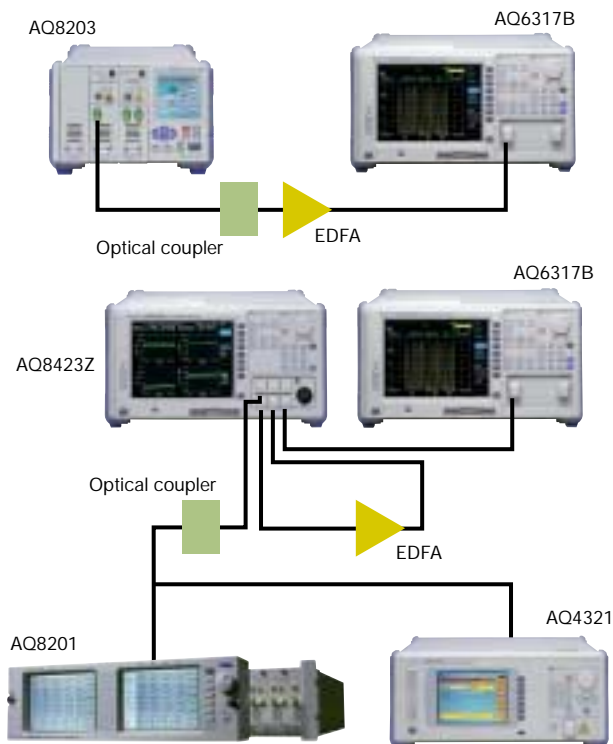


Measures transmission characteristics of 16-channel AWG and displays results on AQ6317B's screen.

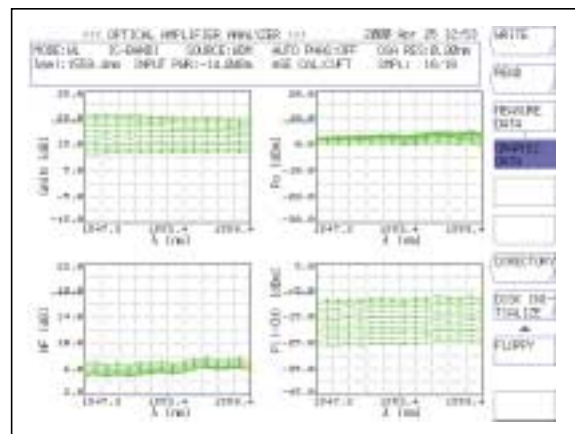
● Optical fiber amplifier (EDFA) evaluation

The ASE interpolation method is used to measure gain and NF, key parameters for optical fiber amplifier evaluation.

In conjunction with the AQ8423Z optical amplifier analyzer, the system can accurately measure gain and NF with the pulse method, which is optimum for evaluation of WDM optical fiber amplifiers.



Measurement example using EDFA analysis function (Measurement results on AQ6317B's screen)



Measurement example of wavelength dependency of gain/NF of EDFA (Measurement results on AQ8423Z's screen)

Specifications

Applicable fibers	SMF, GI (50/125 μm)	
Measurement wavelength range ¹⁾	600 to 1750 nm	
Wavelength accuracy ^{1,3)}	±0.02 nm (1520 to 1580 nm, after calibration with build-in reference light source) ±0.04 nm (1580 to 1620 nm, after calibration with build-in reference light source) ±0.5 nm (600 to 1750 nm)	
Wavelength linearity ^{1,3)}	±0.01 nm (1520 to 1580 nm) ±0.02 nm (1580 to 1620 nm)	
Wavelength repeatability ^{1,3)}	±0.005 nm (1 min)	
Wavelength resolution ^{1,3)}	Max. resolution: 0.015 nm or better (1520 to 1620 nm, resolution setting: 0.01 nm) Resolution setting: 0.01, 0.02, 0.05, 0.1, 0.2, 0.5, 1.0, 2.0 nm	
Resolution accuracy ^{1,3)}	±5 %: (1300 to 1650 nm, resolution: 0.05 nm or more, resolution correction: ON)	
Measurement level range ^{2,3)}	-90 to +20 dBm (1200 to 1650 nm, sensitivity: HIGH3) -80 to +20 dBm (1000 to 1200 nm, sensitivity: HIGH3) -60 to +20 dBm (600 to 1000 nm, sensitivity: HIGH3)	
Level accuracy ^{2,3)}	±0.3 dB (1310/1550 nm, input: -30 dBm, sensitivity: HIGH1-3)	
Level linearity ^{2,3)}	±0.05 dB (input: +10 to -50 dBm, sensitivity: HIGH1-3)	
Level flatness ^{2,3)}	±0.1 dB (1520 to 1580 nm), ±0.2 dB (1580 to 1620 nm)	
Polarization dependency ^{2,3)}	±0.05 dB (1550/1600 nm), ±0.05 dB typ. (1310 nm)	
Dynamic range ³⁾	60 dB (1523 nm, peak ±0.2 nm, resolution: 0.01 nm) 70 dB (1523 nm, peak ±0.4 nm, resolution: 0.01 nm) 45 dB (1523 nm, peak ±0.2 nm, resolution: 0.1 nm)	
Sweep time	Approx. 500 ms (Span: 100 nm or less, sensitivity: NORM, HOLD, ave.: 1, 501 samples, resolution correction: OFF) Approx. 0.5 min (Span: 100 nm or less, sensitivity: HIGH2, ave.: 1, 501 samples, No signal)	
Function	Automatic measurement	Program function (20 program, 200 steps), Long-term measurement function
	Setting of measuring conditions	Span setting: 0 to 1200 nm Measuring sensitivity setting: NORMAL HOLD/AUTO, MID, HIGH1/2/3 Number of averaging setting: 1 to 1000 times Sample number setting: 11 to 20001, AUTO Automatic setting function of measuring conditions Sweep-between-marker function 0 nm sweep function Pulse light measurement function Air/vacuum wavelength measurement function TLS synchronized measurement function

Function	Trace display	Level scale setting: 0.1 to 10 dB/div, linear Simultaneous display of 3 independent traces Max./Min. hold display Roll averaging display Calculation-between-traces display Normalized display Curve-fit display 3D display Split display Power density display, % display, dB/km display Frequency display of horizontal axis scale
	Data analysis	WDM waveform analysis (Wavelength/Level/SNR list display), Optical fiber amplifier analysis (GAIN/NF, Single/Multi channel), PMD analysis, Optical filter analysis, DFB-LD analysis, FP-LD analysis, LED analysis, SMSR analysis, Peak search, bottom search, spectral width search, notch width search Delta marker (max. 200), line marker (analysis range specification) Graph display of long-term measurement result
Memory	Others	Self-wavelength calibration function (using built-in reference light source) Wavelength/Level compensation function, label function, help function
	Build-in FDD	3.5-inch 2HD
	Internal memory	32 traces, 20 programs
Data output	File format	Trace file, program file, measuring condition file, Text file (trace, analysis data, etc.), Graphics file (BMP,TIFF)
	Printer	Built-in high speed printer
Interface	Remote control	GP-IB (2 ports) TLS control interfaces (TTL)
	Others	Sweep trigger input (TTL) Sample enable input (TTL) Sample trigger input (TTL) Analog output (0 to 5 V) Video output (VGA)
Display	9.4-inch color LCD (Resolution: 640 x 480 dots)	
Optical connector	FC (Standard)	
Power requirement	AC 100 to 120/200 to 240 V, 50/60 Hz	
Environmental conditions	Operating temperature: 5 to 40 °C Storage temperature: -10 to +50 °C Humidity: 80 %RH or less (No condensation)	
Dimensions and mass	Approx. 425 (W) x 222 (H) x 450 (D) mm, approx. 30 kg	

Notes:

- 1) Horizontal scale: wavelength display mode
- 2) Vertical scale: absolute power display mode, resolution: 0.05 nm or more, resolution correction: OFF
- 3) At 15 to 30 °C, with 10/125 μm single mode fiber, after 2 hours of warm-up, after optical alignment

Specifications are subject to change without notice.

Ando Electric Co., Ltd.

3-484, Tsukagoshi, Saiwai-ku, Kawasaki, Kanagawa, 212-8519 Japan Phone: +81 (0)44 549 7300 Fax: +81 (0)44 549 7450

Ando Corporation

2021 N. Capitol Avenue, San Jose, CA 95132, U.S.A. Phone: +1 408 941 0100 Fax: +1 408 941 0103
EAST OFFICE: 7617 Standish Place, Rockville, MD 20855, U.S.A. Phone: +1 301 294 3365 Fax: +1 301 294 3359

Ando Europe B.V.

"Vijverdam", Dalsteindreef 57, 1112XC Diemen, The Netherlands Phone: +31(0)20 698 1441 Fax: +31(0)20 699 8938
NIEDERLASSUNG DEUTSCHLAND: Nymphenburger Straße 119 B, D-80636 München, Germany Phone: +49(0)89 143 8150 Fax: +49(0)89 143 81555

Ando Electric Singapore Pte. Ltd.

19 Kim Keat Road #05-03, Jumbo Industrial Building, Singapore 328804 Phone: +65 251 1391 Fax: +65 251 1987

Please visit our website for more information: www.ando.com